

Fabrications and Characteristics of Low-noise La-Ca-Sr-Mn-O Thin-film Thermometers

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ABSTRACT

La_{0.75}Ca_{0.15}Sr_{0.1}MnO₃ (LCSMO) thin films were grown on NdGaO₃(110) substrates by using RF magnetron sputtering. Here the samples were deposited at different growth temperatures to probe the effect of growth temperature on this film properties. We used the standard 4-probe measurement to obtain the resistance-temperature curves. The crystalline structure and the strains in films were characterized by the X-ray diffractometer. The optimum performance is found in LCSMO grown at 610 °C with low strain, which show a temperature coefficient of resistance (TCR) ~ 4.9 %K⁻¹ at 301 K and a noise equivalent temperature (NET) of 8×10^{-7} KHz^{-0.5} at 300 K with $f = 30$ Hz and $I = 0.3$ mA. This obtained NET value is much lower than those of other uncooled thermometers such as semiconducting YBa₂Cu₃O₆, or vanadium oxides. We demonstrate that the LCSMO films have real potential for the application on uncooled bolometric devices.

Keywords : infrared detector、 temperature coefficient of resistance、 colossal magnetoresistance material

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